

Form PTO 1449 U.S. DEPARTMENT OF COMMERCE (Modified) PATENT AND TRADEMARK OFFICE			ATTY DOCKET NO.		SERIAL NO. New US PCT application		
			ARK OFFICE	217829US0PCT		based on PCT/JP00/08342	
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U.S. PATENT DOCUMENTS							
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Inn	AO	11-77938	03/23/99	JP			No
	AP	11-147569	06/02/99	JP			No .
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OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
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